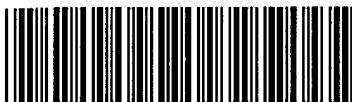


**Search Notes**

Application/Control No.

09/242,772

Examiner

Young J. Kim

Applicant(s)/Patent under  
Reexamination

VAN DE VEN ET AL.

Art Unit

1637

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
SEQ ID NO: 116 - interference database via STIC.	12/19/2005	YJK